



Dual N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY				
	V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A)	Q _g (Typ)
Channel 1	30	0.035 at V _{GS} = 10 V	6 ^a	4.5 nC
		0.042 at V _{GS} = 4.5 V	6 ^a	
Channel 2	30	0.028 at V _{GS} = 10 V	6 ^a	5.5 nC
		0.035 at V _{GS} = 4.5 V	6 ^a	

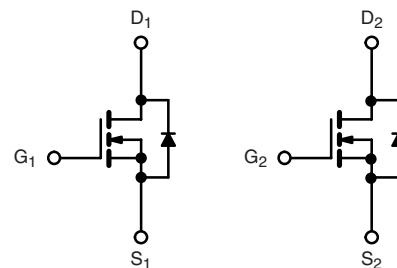
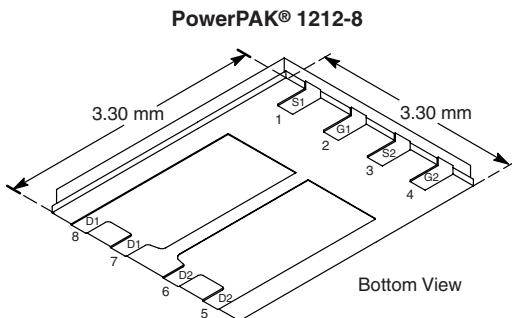
FEATURES

- TrenchFET® Power MOSFETs

RoHS
COMPLIANT

APPLICATIONS

- Notebook PC System Power
- Low Current POL



Ordering Information: Si7224DN-T1-E3 (Lead (Pb)-free)

N-Channel MOSFET

N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Channel 1	Channel 2	Unit
Drain-Source Voltage	V _{DS}	30	30	V
Gate-Source Voltage	V _{GS}	± 16	± 20	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I _D	6 ^a	A
	T _C = 70 °C		6 ^a	
	T _A = 25 °C		6 ^{a, b, c}	
	T _A = 70 °C		5.2 ^{b, c}	
Pulsed Drain Current	I _{DM}	25	30	
Source Drain Current Diode Current	T _C = 25 °C	I _S	6 ^a	W
	T _A = 25 °C		1.7 ^{b, c}	
Maximum Power Dissipation	T _C = 25 °C	P _D	17.8	
	T _C = 70 °C		11.4	
	T _A = 25 °C		2.5 ^{b, c}	
	T _A = 70 °C		1.6 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150		°C
Soldering Recommendations (Peak Temperature) ^{d, e}		260		

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Channel 1		Channel 2		Unit
		Typ	Max	Typ	Max	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	40	50	38	48
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	5.6	7	4.3	5.4

Notes:

- a. Package limited.
- b. Surface Mounted on 1" x 1" FR4 Board.
- c. t = 10 s.
- d. See Solder Profile (<http://www.vishay.com/ppg?73257>). The PowerPAK 1212-8 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under Steady State conditions is 94 °C/W.

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	Ch 1 30 Ch 2 30			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$	Ch 1 Ch 2 37 32			mV/°C
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$	$I_D = 250 \mu\text{A}$	Ch 1 Ch 2 - 5 - 6			
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Ch 1 Ch 2 1 1.5		2.2 3	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$ $V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	Ch 1 Ch 2 ± 100 ± 100			nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$	Ch 1 Ch 2 1 1			μA
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$	Ch 1 Ch 2 10 10			
		$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	Ch 1 Ch 2 15 15			
		$V_{GS} = 10 \text{ V}, I_D = 6.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 7.4 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 5.9 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 6.6 \text{ A}$	Ch 1 Ch 2 0.027 0.022 0.032 0.029	0.035 0.028 0.042 0.035		
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 6.5 \text{ A}$	Ch 1 Ch 2 22			S
		$V_{DS} = 15 \text{ V}, I_D = 7.4 \text{ A}$	Ch 2 21			
Dynamic^a						
Input Capacitance	C_{iss}	Channel 1 $V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	Ch 1 Ch 2 570 720			pF
Output Capacitance	C_{oss}		Ch 1 Ch 2 80 115			
Reverse Transfer Capacitance	C_{rss}		Ch 1 Ch 2 35 50			
Total Gate Charge	Q_g		Ch 1 Ch 2 9.5 12	14.5 18		nC
	Channel 1 $V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 6.5 \text{ A}$	Ch 1 Ch 2 4.5 5.5	7 8.5			
Gate-Source Charge		Q_{gs}	Ch 1 Ch 2 1.5 2.5			nC
Gate-Drain Charge		Q_{gd}	Ch 1 Ch 2 1.2 1.7			
Gate Resistance		R_g	Ch 1 Ch 2 3.3 2.7			

Notes:

- a. Guaranteed by design, not subject to production testing.
 b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.



New Product

Si7224DN

Vishay Siliconix

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Dynamic^a						
Turn-On Delay Time	$t_{d(on)}$	Channel 1 $V_{DD} = 15 \text{ V}$, $R_L = 2.9 \Omega$ $I_D \approx 5.2 \text{ A}$, $V_{GEN} = 4.5 \text{ V}$, $R_g = 1 \Omega$	Ch 1	12	20	ns
Rise Time	t_r		Ch 2	20	30	
Turn-Off Delay Time	$t_{d(off)}$		Ch 1	12	20	
Fall Time	t_f		Ch 2	12	20	
Turn-On Delay Time	$t_{d(on)}$		Ch 1	12	20	
Rise Time	t_r		Ch 2	10	15	
Turn-Off Delay Time	$t_{d(off)}$		Ch 1	15	25	
Fall Time	t_f		Ch 2	10	15	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$	Ch 1		6	A
Pulse Diode Forward Current ^a	I_{SM}		Ch 2		6	
Body Diode Voltage	V_{SD}	$I_S = 5.2 \text{ A}$, $V_{GS} = 0 \text{ V}$	Ch 1		25	V
Body Diode Reverse Recovery Time	t_{rr}	$I_S = 5.9 \text{ A}$, $V_{GS} = 0 \text{ V}$	Ch 2		30	
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F = 5.2 \text{ A}$, $di/dt = 100 \text{ A}/\mu\text{s}$, $T_J = 25^\circ\text{C}$	Ch 1	0.8	1.2	nC
Reverse Recovery Fall Time	t_a		Ch 2	0.8	1.2	
Reverse Recovery Rise Time	t_b		Ch 1	15	30	ns
			Ch 2	20	40	
			Ch 1	10	20	ns
			Ch 2	12	20	
			Ch 1	9		ns
			Ch 2	12		
			Ch 1	6		ns
			Ch 2	8		

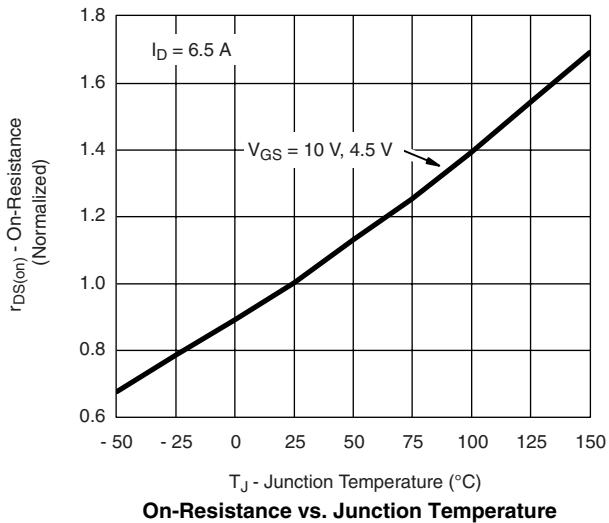
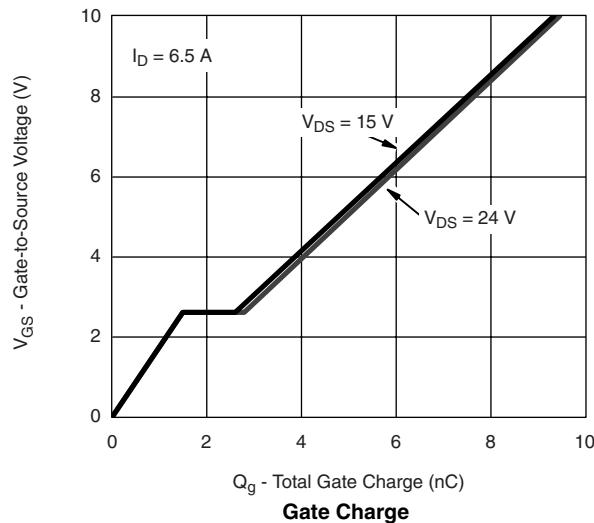
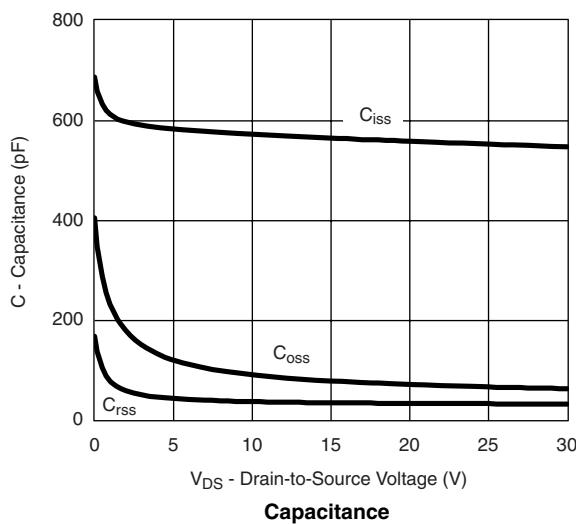
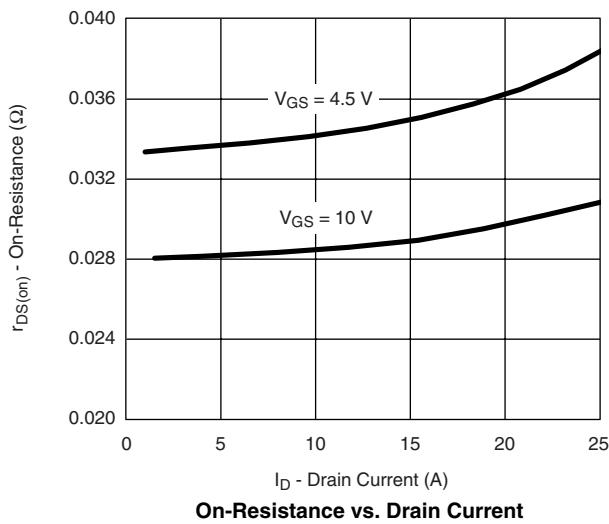
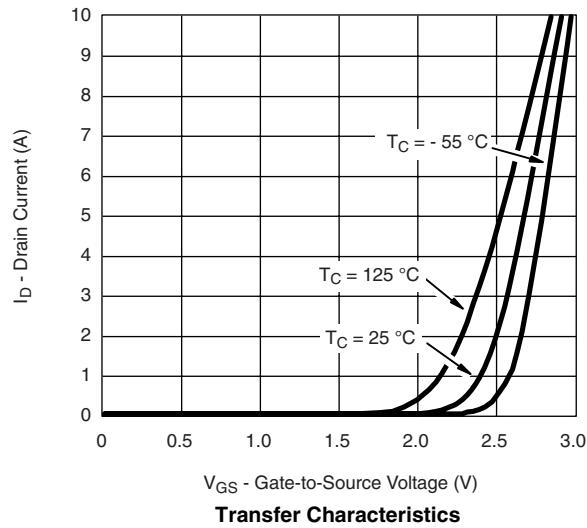
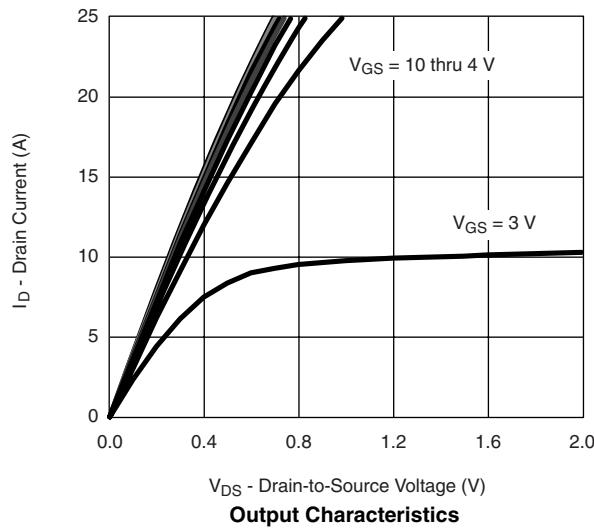
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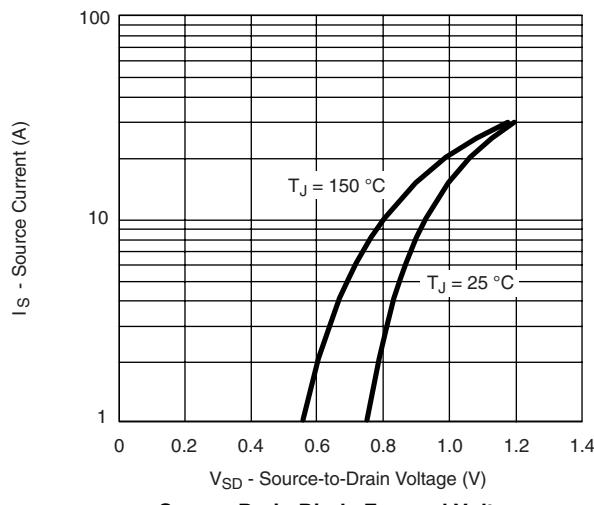
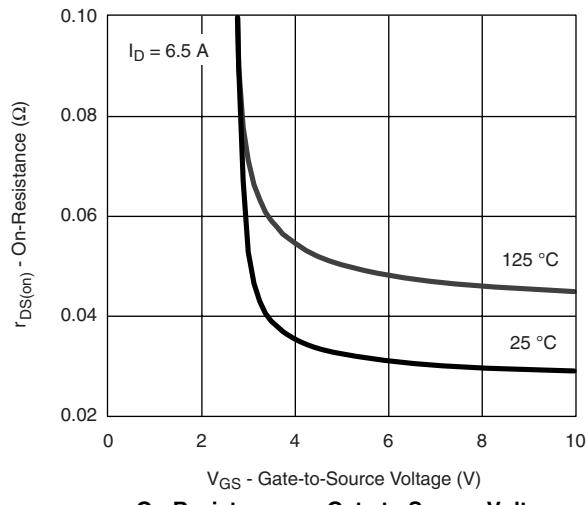
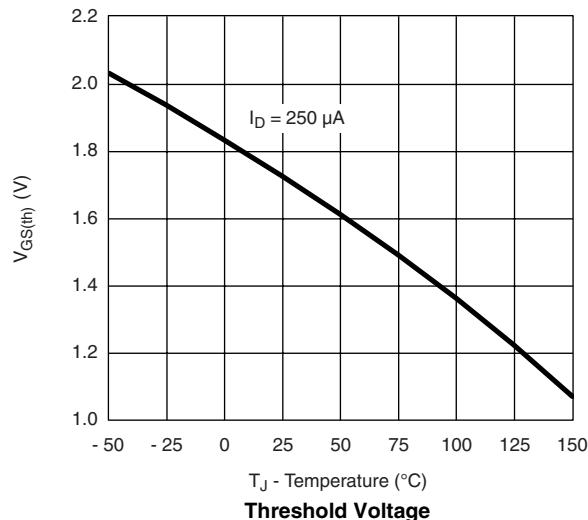
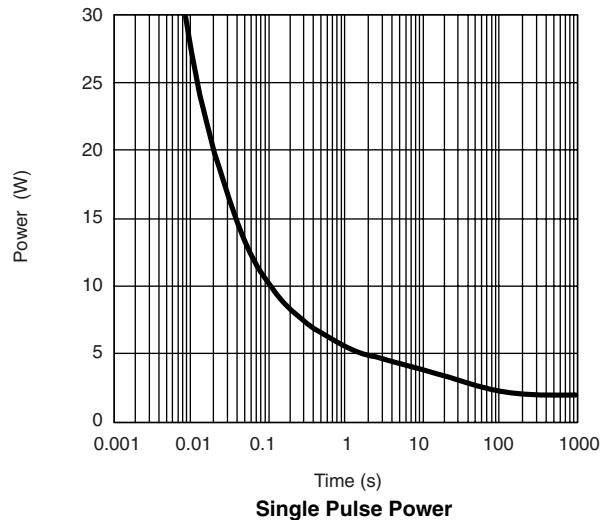
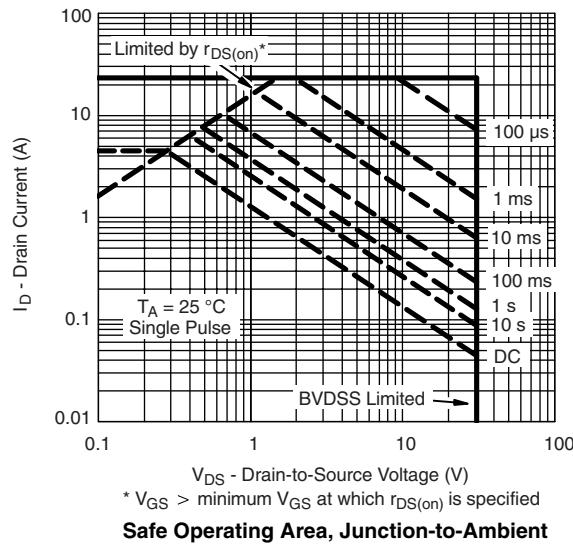
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- b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

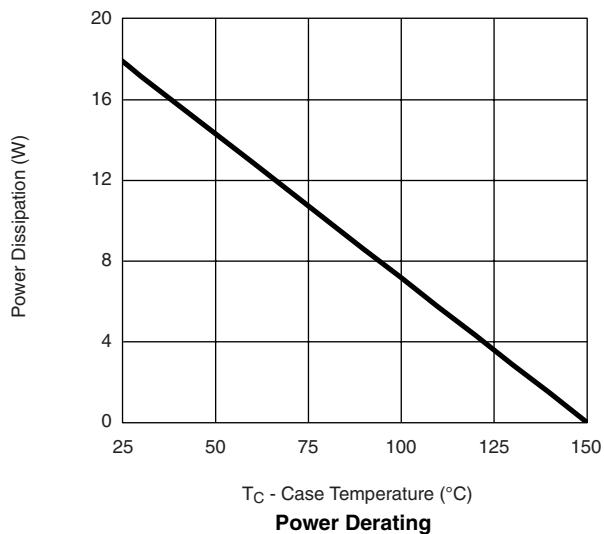
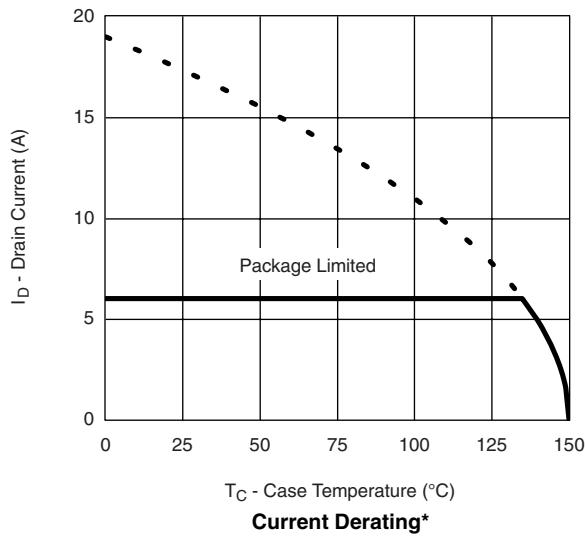
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Si7224DN

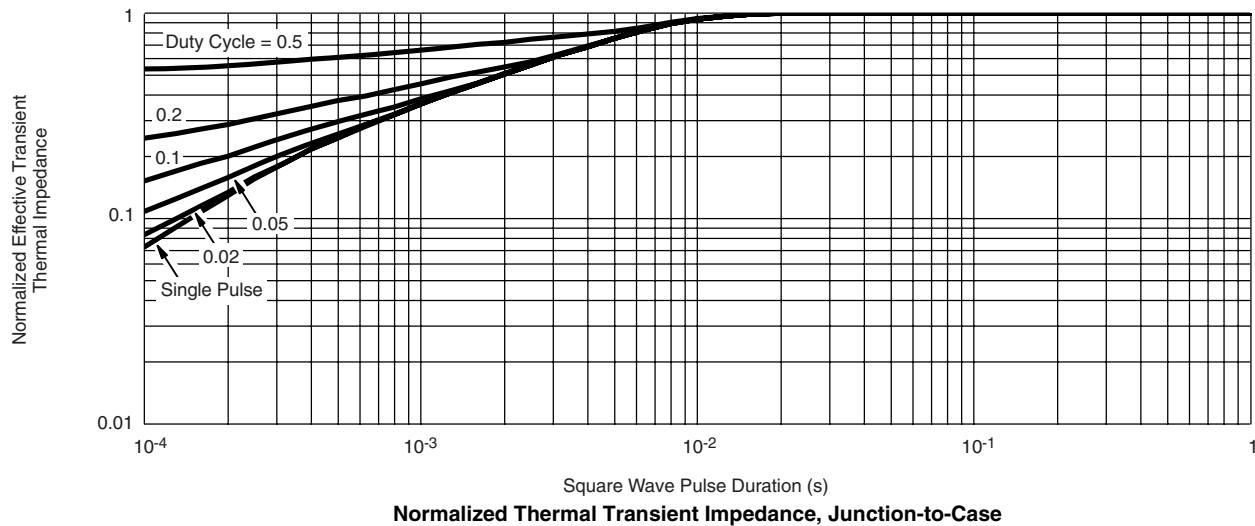
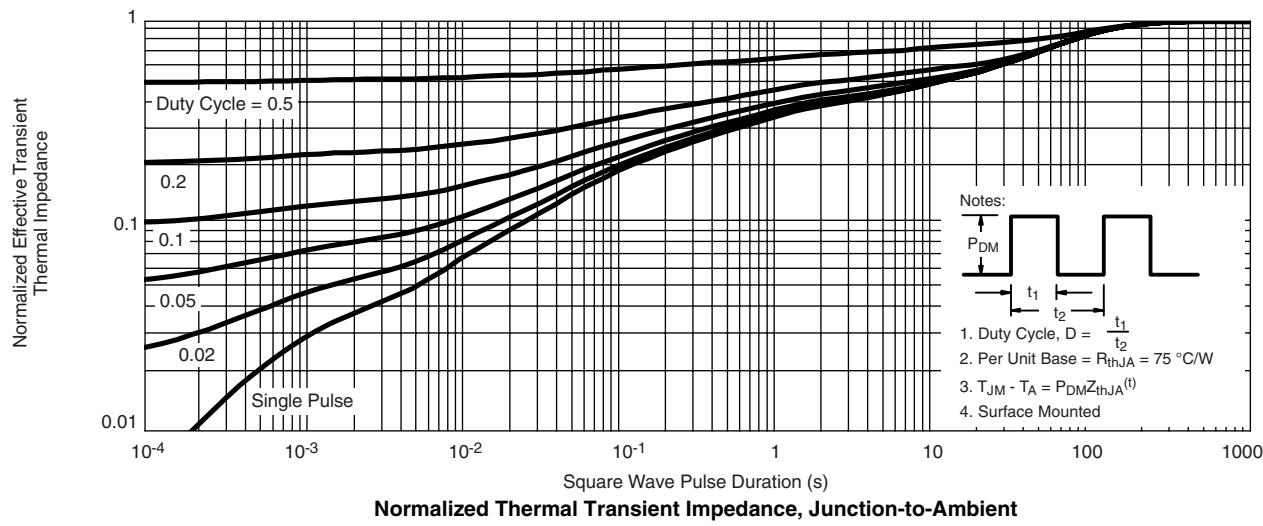
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**CHANNEL 1 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

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Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source Voltage

Threshold Voltage

Single Pulse Power

* $V_{GS} >$ minimum V_{GS} at which $r_{DS(on)}$ is specified
Safe Operating Area, Junction-to-Ambient

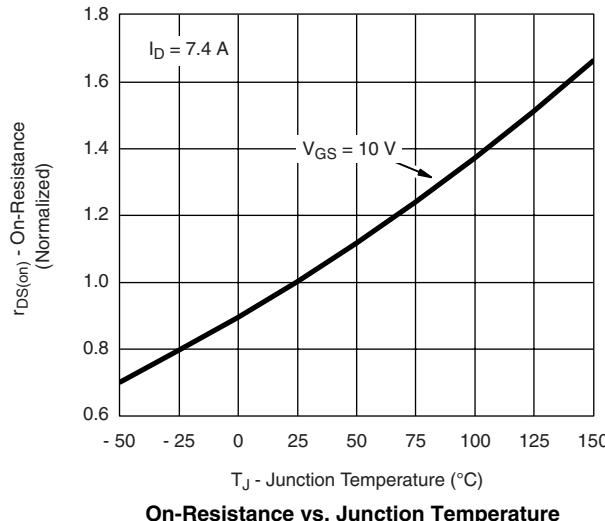
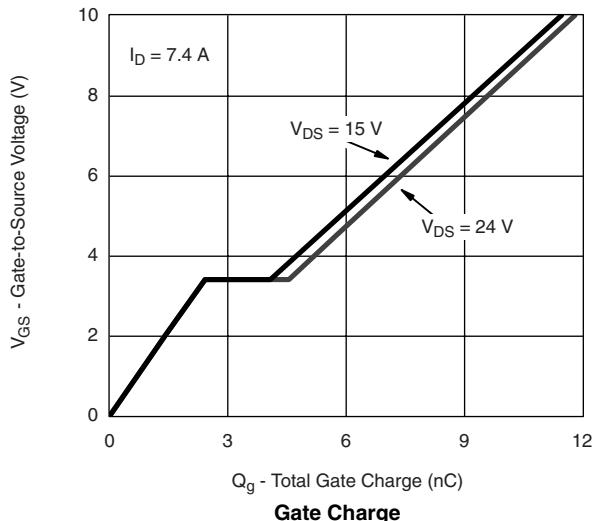
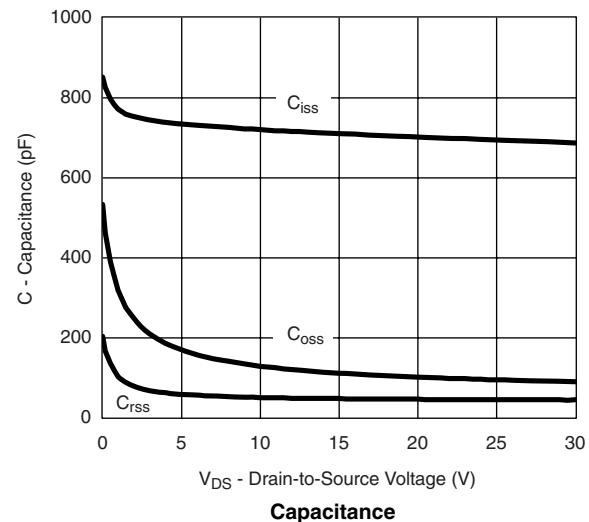
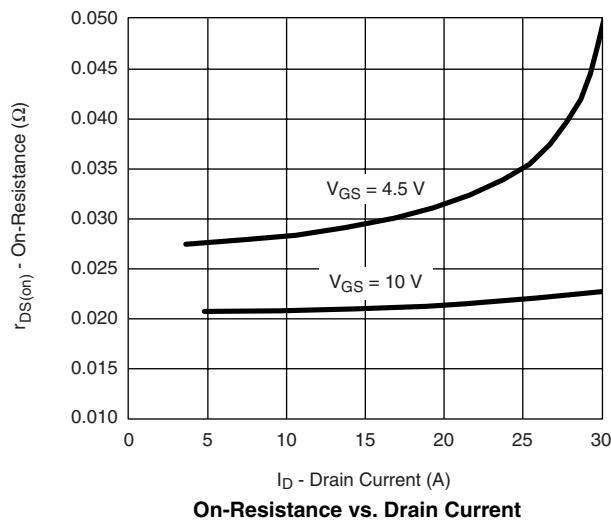
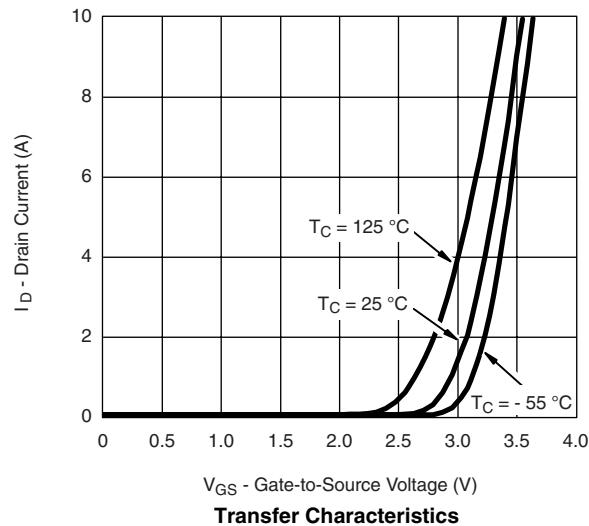
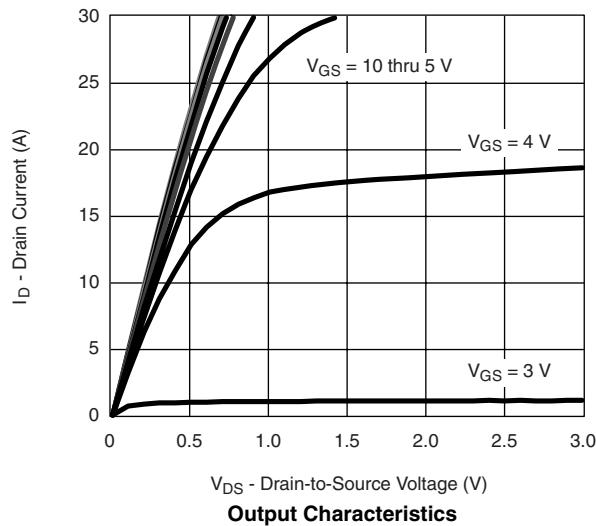
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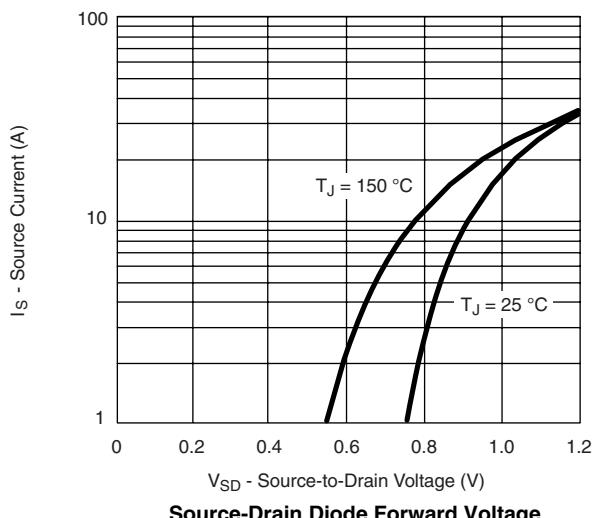
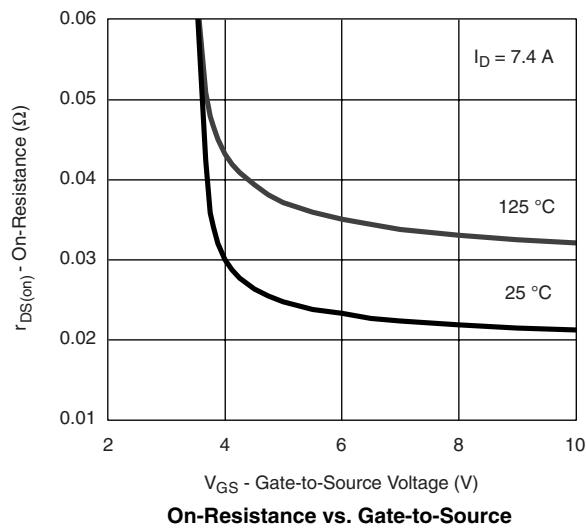
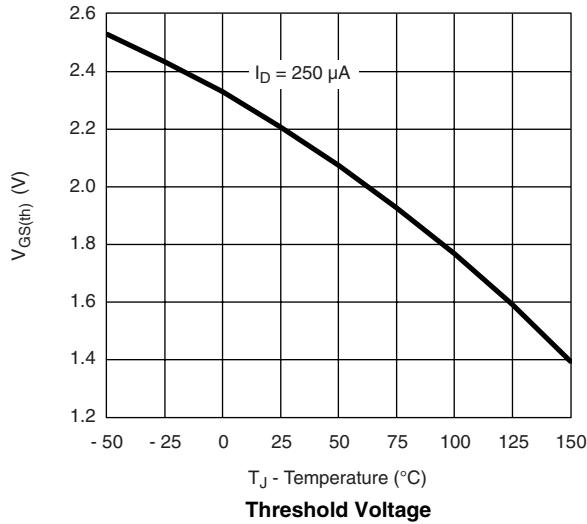
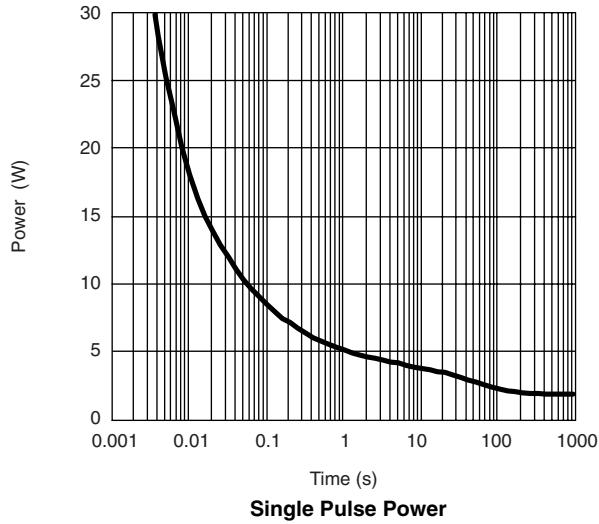
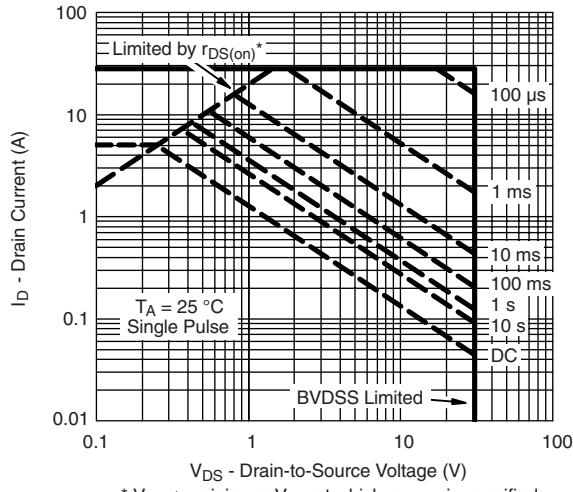
* The power dissipation P_D is based on $T_{J(\max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

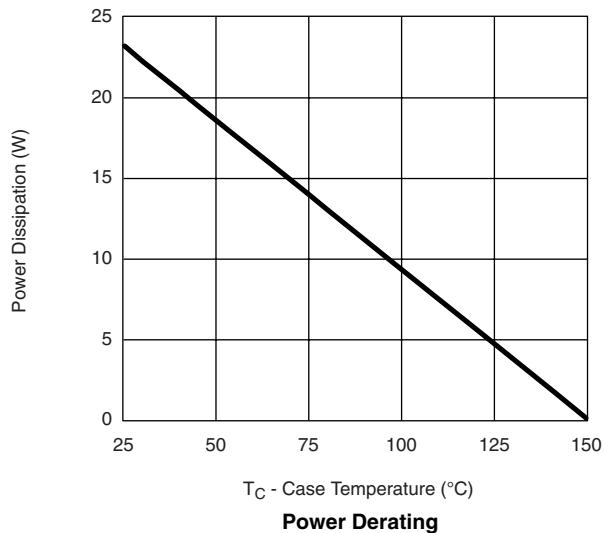
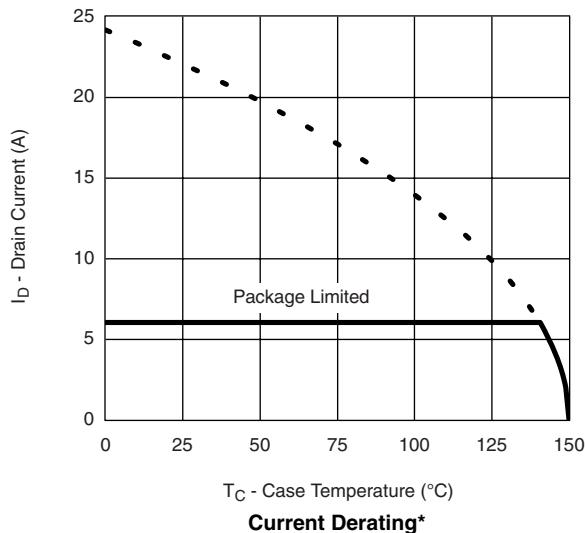
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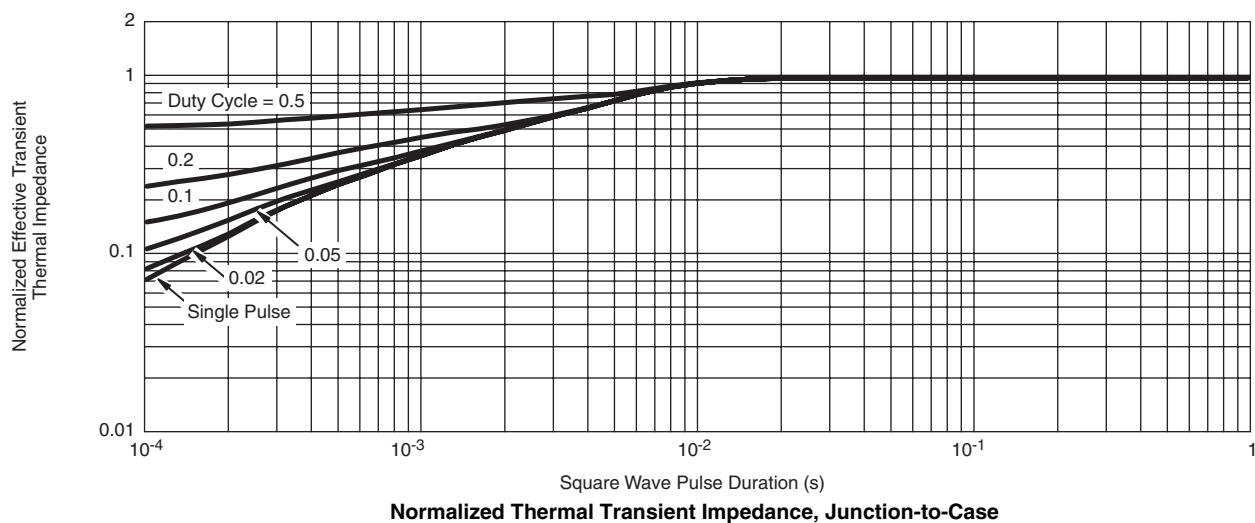
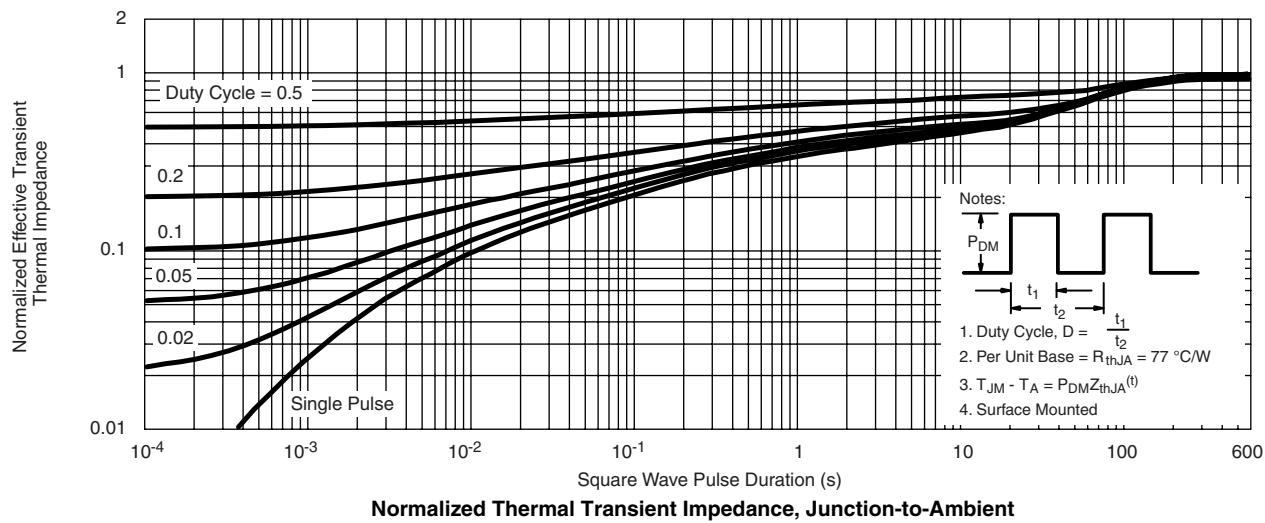
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**CHANNEL 2 TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

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Source-Drain Diode Forward Voltage

On-Resistance vs. Gate-to-Source

Threshold Voltage

Single Pulse Power

 $* V_{GS} > \text{minimum } V_{GS} \text{ at which } r_{DS(on)} \text{ is specified}$
Safe Operating Area, Junction-to-Ambient

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CHANNEL 2 TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


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